List of Publications by Year in descending order

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#	Article	IF	CITATIONS
1	Low-temperature polysilicon thin film transistors on polyimide substrates for electronics on plastic. Solid-State Electronics, 2008, 52, 348-352.	0.8	122
2	High performance printed N and P-type OTFTs enabling digital and analog complementary circuits on flexible plastic substrate. Solid-State Electronics, 2013, 84, 167-178.	0.8	72
3	High-field-effect-mobility pentacene thin-film transistors with polymethylmetacrylate buffer layer. Applied Physics Letters, 2005, 86, 203505.	1.5	70
4	Dopant redistribution and electrical activation in silicon following ultra-low energy boron implantation and excimer laser annealing. Physical Review B, 2003, 67, .	1.1	60
5	Contact effects in high performance fully printed p-channel organic thin film transistors. Applied Physics Letters, 2011, 99, .	1.5	60
6	Kink effect in short-channel polycrystalline silicon thin-film transistors. Applied Physics Letters, 2004, 85, 3113-3115.	1.5	56
7	Hot carrier effects in n-channel polycrystalline silicon thin-film transistors: a correlation between off-current and transconductance variations. IEEE Transactions on Electron Devices, 1994, 41, 340-346.	1.6	54
8	"Hump―characteristics and edge effects in polysilicon thin film transistors. Journal of Applied Physics, 2008, 104, .	1.1	54
9	Aging effects in pentacene thin-film transistors: Analysis of the density of states modification. Applied Physics Letters, 2006, 88, 193508.	1.5	48
10	Current spreading effects in fully printed p-channel organic thin film transistors with Schottky source–drain contacts. Organic Electronics, 2013, 14, 86-93.	1.4	44
11	Surface-scattering effects in polycrystalline silicon thin-film transistors. Applied Physics Letters, 2003, 82, 3119-3121.	1.5	43
12	Polysilicon TFT Structures for Kink-Effect Suppression. IEEE Transactions on Electron Devices, 2004, 51, 1135-1142.	1.6	40
13	Lateral growth control in excimer laser crystallized polysilicon. Thin Solid Films, 1999, 337, 137-142.	0.8	39
14	Controlling field-effect mobility in pentacene-based transistors by supersonic molecular-beam deposition. Applied Physics Letters, 2006, 88, 132106.	1.5	39
15	Determination of hot-carrier induced interface state density in polycrystalline silicon thin-film transistors. Journal of Applied Physics, 1998, 84, 2341-2348.	1.1	37
16	Ultra-shallow junction formation by excimer laser annealing and low energy (<1 keV) B implantation: A two-dimensional analysis. Nuclear Instruments & Methods in Physics Research B, 2002, 186, 401-408.	0.6	36
17	Principle of operation and modeling of source-gated transistors. Journal of Applied Physics, 2013, 114, .	1.1	35
18	Redistribution and electrical activation of ultralow energy implanted boron in silicon following laser annealing. Journal of Vacuum Science & Technology an Official Journal of the American Vacuum Society B, Microelectronics Processing and Phenomena. 2002. 20. 644.	1.6	34

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19	Carbon nanotube semitransparent electrodes for amorphous silicon based photovoltaic devices. Applied Physics Letters, 2011, 98, .	1.5	34
20	Variation-based design of an AM demodulator in a printed complementary organic technology. Organic Electronics, 2014, 15, 904-912.	1.4	34
21	Unified drain-current model of complementary p- and n-type OTFTs. Organic Electronics, 2015, 22, 5-11.	1.4	34
22	Two-dimensional delineation of ultrashallow junctions obtained by ion implantation and excimer laser annealing. Applied Physics Letters, 2000, 77, 552-554.	1.5	33
23	Analysis of contact effects in fully printed p-channel organic thin film transistors. Organic Electronics, 2012, 13, 2017-2027.	1.4	33
24	Aging effects and electrical stability in pentacene thin film transistors. Thin Solid Films, 2007, 515, 7546-7550.	0.8	31
25	Pentacene TFTs with parylene passivation layer. Thin Solid Films, 2009, 517, 6283-6286.	0.8	31
26	Depth distribution of B implanted in Si after excimer laser irradiation. Applied Physics Letters, 2005, 86, 051909.	1.5	29
27	Numerical analysis of electrical characteristics of polysilicon thin film transistors fabricated by excimer laser crystallisation. Electronics Letters, 1998, 34, 924.	0.5	28
28	Analysis of electrical characteristics of gate overlapped lightly doped drain (GOLDD) polysilicon thin-film transistors with different LDD doping concentration. IEEE Transactions on Electron Devices, 2003, 50, 2425-2433.	1.6	28
29	Crystallization mechanisms in laser irradiated thin amorphous silicon films. Thin Solid Films, 2003, 427, 91-95.	0.8	27
30	Effect of active layer thickness on electrical characteristics of pentacene TFTs with PMMA buffer layer. Solid-State Electronics, 2008, 52, 412-416.	0.8	27
31	Short channel effects in polysilicon thin film transistors. Thin Solid Films, 2005, 487, 221-226.	0.8	26
32	Contact Effects in Amorphous InGaZnO Thin Film Transistors. Journal of Display Technology, 2014, 10, 956-961.	1.3	25
33	Analysis of self-heating related instability in n-channel polysilicon thin film transistors fabricated on polyimide. Thin Solid Films, 2009, 517, 6371-6374.	0.8	24
34	Fabrication and nonlinear characterization of GaN HEMTs on SiC and sapphire for high-power applications. International Journal of RF and Microwave Computer-Aided Engineering, 2006, 16, 70-80.	0.8	23
35	A Two-Pass Excimer Laser Annealing Process to Control Amorphous Silicon Crystallization. Japanese Journal of Applied Physics, 1999, 38, L907-L910.	0.8	22
36	Advanced excimer laser crystallization techniques. Thin Solid Films, 2001, 383, 39-44.	0.8	22

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37	Material modifications induced by laser annealing in two-dimensional structures. Applied Physics Letters, 2004, 84, 4738-4740.	1.5	22
38	Low-temperature, self-catalyzed growth of Si nanowires. Nanotechnology, 2010, 21, 255601.	1.3	22
39	Dispersive charge injection model for hydrogenated amorphous silicon/amorphous silicon dioxide thinâ€film transistor instability. Applied Physics Letters, 1991, 59, 826-828.	1.5	21
40	Hot-carrier-induced degradation of LDD polysilicon TFTs. IEEE Transactions on Electron Devices, 2006, 53, 43-50.	1.6	21
41	Low-Temperature Annealing Combined with Laser Crystallization for Polycrystalline Silicon TFTs on Polymeric Substrate. Journal of the Electrochemical Society, 2008, 155, H764.	1.3	21
42	Self-heating effects in polycrystalline silicon thin film transistors. Applied Physics Letters, 2006, 89, 093509.	1.5	20
43	Threshold voltage in short channel polycrystalline silicon thin film transistors: Influence of drain induced barrier lowering and floating body effects. Journal of Applied Physics, 2010, 107, .	1.1	20
44	Temperature dependence of the transfer characteristics of polysilicon thin film transistors fabricated by excimer laser crystallization. Journal of Applied Physics, 1999, 85, 616-618.	1.1	19
45	Light polarization control in strain-engineered GaAsN/GaAsN:H heterostructures. Applied Physics Letters, 2009, 94, 261905.	1.5	19
46	Influence of structural properties on environmental stability of pentacene thin film transistors. Organic Electronics, 2011, 12, 447-452.	1.4	19
47	Excimer laser crystallization techniques for polysilicon TFTs. Applied Surface Science, 2000, 154-155, 95-104.	3.1	18
48	High performance printed N and P-type OTFTs for complementary circuits on plastic substrate. , 2012, , .		18
49	A novel fabrication process for polysilicon thin film transistors with source/drain contacts formed by deposition and lift-off of highly doped layers. Solid-State Electronics, 2002, 46, 1351-1358.	0.8	17
50	Analysis of Self-Heating-Related Instability in Self-Aligned p-Channel Polycrystalline-Silicon Thin-Film Transistors. IEEE Electron Device Letters, 2010, 31, 830-832.	2.2	17
51	Evidence of Correlated Mobility Fluctuations in p-Type Organic Thin-Film Transistors. IEEE Electron Device Letters, 2015, 36, 390-392.	2.2	17
52	Numerical Analysis of the Electrical Characteristics of Gate Overlapped Lightly Doped Drain Polysilicon Thin Film Transistors. Japanese Journal of Applied Physics, 1999, 38, 3475-3481.	0.8	16
53	Pentacene thin film transistors with (polytetrafluoroethylene) PTFE-like encapsulation layer. Organic Electronics, 2011, 12, 119-124.	1.4	16
54	A Compact SPICE Model for Organic TFTs and Applications to Logic Circuit Design. IEEE Nanotechnology Magazine, 2016, 15, 754-761.	1.1	16

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55	A DC and small signal AC model for organic thin film transistors including contact effects and non quasi static regime. Organic Electronics, 2017, 41, 345-354.	1.4	16
56	Hot carrier-induced degradation of gate overlapped lightly doped drain (GOLDD) polysilicon TFTs. IEEE Transactions on Electron Devices, 2002, 49, 636-642.	1.6	15
57	The effect of excimer laser pretreatment on diffusion and activation of boron implanted in silicon. Applied Physics Letters, 2005, 87, 192109.	1.5	15
58	Analysis of electrical characteristics of high performance pentacene thin-film transistors with PMMA buffer layer. Journal of Non-Crystalline Solids, 2006, 352, 1765-1768.	1.5	15
59	Excimer Laser annealing for shallow junction formation in Si power MOS devices. Thin Solid Films, 2006, 504, 2-6.	0.8	15
60	Modeling of Capacitance Characteristics of Printed p-Type Organic Thin-Film Transistors. IEEE Transactions on Electron Devices, 2014, 61, 4120-4127.	1.6	15
61	Three-dimensional characterization of OTFT on modified hydrophobic flexible polymeric substrate by low energy Cs+ ion sputtering. Applied Surface Science, 2018, 448, 628-635.	3.1	15
62	Gravure printed organic thin film transistors: Study on the ink printability improvement. Organic Electronics, 2018, 61, 104-112.	1.4	15
63	Low voltage operation a-Si:H thin film transistors with very thin PECVD a-SiO2 gate dielectric. Journal of Non-Crystalline Solids, 1989, 115, 144-146.	1.5	14
64	Electrical stability in self-aligned p-channel polysilicon thin film transistors. Thin Solid Films, 2007, 515, 7571-7575.	0.8	14
65	Effect of hydrogen incorporation temperature inin plane-engineered GaAsNâ^•GaAsN:H heterostructures. Applied Physics Letters, 2008, 92, 221901.	1.5	14
66	Design of analog and digital building blocks in a fully printed complementary organic technology. , 2012, , .		14
67	Fabrication of ultra-shallow junctions with high electrical activation by excimer laser annealing. Materials Science in Semiconductor Processing, 2001, 4, 417-423.	1.9	13
68	Integration of Melting Excimer Laser Annealing in Power MOS Technology. IEEE Transactions on Electron Devices, 2007, 54, 852-860.	1.6	13
69	Self-heating effects on the electrical instability of fully printed p-type organic thin film transistors. Applied Physics Letters, 2012, 101, .	1.5	13
70	Highly sensitive organic phototransistor for flexible optical detector arrays. Organic Electronics, 2022, 102, 106452.	1.4	13
71	SuMBE based organic thin film transistors. Synthetic Metals, 2004, 146, 291-295.	2.1	12
72	Stable p-channel polysilicon thin film transistors fabricated by laser doping technique. Thin Solid Films, 2005, 487, 232-236.	0.8	12

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73	Grain boundary evaluation in sequentially laterally solidified polycrystalline-silicon devices. Journal of Applied Physics, 2007, 101, 094502.	1.1	12
74	A new self-consistent model for the analysis of hot-carrier induced degradation in lightly doped drain (LDD) and gate overlapped LDD polysilicon TFTs. Thin Solid Films, 2003, 427, 117-122.	0.8	11
75	Electrical activation phenomena induced by excimer laser annealingin B-implanted silicon. Applied Physics Letters, 2004, 85, 2268-2270.	1.5	11
76	Role of gate oxide thickness in controlling short channel effects in polycrystalline silicon thin film transistors. Applied Physics Letters, 2009, 95, .	1.5	11
77	Correlated Mobility Fluctuations and Contact Effects in p-Type Organic Thin-Film Transistors. IEEE Transactions on Electron Devices, 2016, 63, 1239-1245.	1.6	11
78	Numerical simulation of parasitic resistance effects in polycrystalline silicon TFTs. IEEE Transactions on Electron Devices, 2006, 53, 573-577.	1.6	10
79	Giant and reversible enhancement of the electrical resistance of GaAs1â^'xNxby hydrogen irradiation. Physical Review B, 2011, 84, .	1.1	10
80	Analysis of short channel effects in poly-Si thin film transistors: A new method. Microelectronic Engineering, 1992, 19, 183-186.	1.1	9
81	Hot carrier effects in polycrystalline silicon thin-film transistors: analysis of electrical characteristics and noise performance modifications. Microelectronics Reliability, 1999, 39, 45-52.	0.9	9
82	Enhanced boron diffusion in excimer laser preannealed Si. Applied Physics Letters, 2005, 86, 151902.	1.5	9
83	Hot-carrier effects in p-channel polycrystalline silicon thin film transistors. Applied Physics Letters, 2006, 89, 183518.	1.5	9
84	In-plane band gap modulation investigated by secondary electron imaging of GaAsN/GaAsN:H heterostructures. Applied Physics Letters, 2008, 93, 102116.	1.5	9
85	Space-charge photomodulation in metal/insulator/amorphous semiconductor structures (TFTs). IEEE Transactions on Electron Devices, 1989, 36, 2825-2828.	1.6	8
86	Hydrogenated amorphous silicon technology for chemically sensitive thin-film transistors. Sensors and Actuators B: Chemical, 1992, 6, 29-33.	4.0	8
87	Determination of excess current due to impact ionization in polycrystalline silicon thin-film transistors. Solid-State Electronics, 1998, 42, 613-618.	0.8	8
88	Boron distribution in silicon after multiple pulse excimer laser annealing. Applied Physics Letters, 2005, 87, 081901.	1.5	8
89	Modelling velocity saturation and kink effects in p-channel polysilicon thin-film transistors. Thin Solid Films, 2007, 515, 7417-7421.	0.8	8
90	Effective channel length and parasitic resistance determination in non self-aligned low temperature polycrystalline silicon thin film transistors. Thin Solid Films, 2009, 517, 6353-6357.	0.8	8

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91	Quantum confinement effects in hydrogen-intercalatedGa1â^'xAsxNx-GaAs1â^'xNx:Hplanar heterostructures investigated by photoluminescence spectroscopy. Physical Review B, 2010, 81, .	1.1	8
92	The Role of Defective Regions Near the Contacts on the Electrical Characteristics of Bottom-Gate Bottom-Contact Organic TFTs. Journal of Display Technology, 2016, 12, 252-257.	1.3	8
93	Dual-ion-beam sputtering technique for the production of hydrogenated amorphous silicon. Thin Solid Films, 1984, 120, 215-222.	0.8	7
94	a - Si1â^'xGex: H alloys for solar cells. Journal of Non-Crystalline Solids, 1987, 97-98, 1075-1078.	1.5	7
95	Transport properties of plasma-deposited amorphous silicon dioxide. Journal of Non-Crystalline Solids, 1989, 115, 123-125.	1.5	7
96	Density of states and photoconductivity light degradation in a-Si:H at different temperatures. Journal of Non-Crystalline Solids, 1996, 198-200, 482-485.	1.5	7
97	Electrical characterization of directionally solidified polycrystalline silicon. Journal of Applied Physics, 2005, 98, 033702.	1.1	7
98	Interdigitated sensorial system on flexible substrate. , 2008, , .		7
99	A large signal non quasi static model of printed organic TFTs and simulation of CMOS circuits. , 2017, , ·		7
100	Experimental and theoretical evidence of space-charge photomodulation in metal/insulator/amorphous semiconductor structures. Journal of Non-Crystalline Solids, 1989, 114, 378-380.	1.5	6
101	Source-Drain Metal Contact Effects in Short-Channel a-Si:H Thin-Film Transistors. Japanese Journal of Applied Physics, 1990, 29, L2353-L2356.	0.8	6
102	Observation of super lateral growth in long pulse (170 ns) excimer laser crystallization of a-Si films. Thin Solid Films, 2003, 427, 319-323.	0.8	6
103	Modelling Velocity Saturation Effects in Polysilicon Thin-Film Transistors. Japanese Journal of Applied Physics, 2006, 45, 4374-4377.	0.8	6
104	Role of field enhanced mechanisms and impact ionization on the threshold voltage of short channel polycrystalline silicon thin film transistors. Applied Physics Letters, 2008, 93, 193512.	1.5	6
105	Negative bias–temperature stress in non-self-aligned p-channel polysilicon TFTs. Thin Solid Films, 2009, 517, 6379-6382.	0.8	6
106	Downscaling effects on self-heating related instabilities in p-channel polycrystalline silicon thin film transistors. Applied Physics Letters, 2011, 99, .	1.5	6
107	Analysis of Kink Effect and Short Channel Effects in Fully Self-Aligned Gate Overlapped Lightly Doped Drain Polysilicon TFTs. Journal of Display Technology, 2013, 9, 764-769.	1.3	6

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109	Hybrid Electrothermal Simulations of GaN HEMT Devices Based on Self-Heating Free Virtual Electrical Characteristics. IEEE Transactions on Electron Devices, 2021, 68, 3740-3747.	1.6	6
110	Effects of tunneling ona‣i:H Schottky barriers. Journal of Applied Physics, 1987, 62, 3285-3287.	1.1	5
111	Study of the defects induced by lowâ€energy (100 eV) hydrogenâ€ions on amorphous silicon dioxide. Applied Physics Letters, 1992, 60, 1564-1566.	1.5	5
112	Hot-hole-induced degradation in polycrystalline silicon thin-film transistors: experimental and theoretical analysis. IET Circuits, Devices and Systems, 1994, 141, 33.	0.6	5
113	Temperature analysis of polysilicon thin-film transistors made by excimer laser crystallization. Thin Solid Films, 1999, 337, 196-199.	0.8	5
114	Low-frequency noise in gate overlapped lightly doped drain polycrystalline silicon thin-film transistors. Applied Physics Letters, 2000, 76, 3268-3270.	1.5	5
115	Lateral growth control by thickness spatial modulation of amorphous silicon film. Thin Solid Films, 2003, 427, 314-318.	0.8	5
116	Noise performance of polycrystalline silicon thin-film transistors made by sequential lateral solidification. Applied Physics Letters, 2003, 82, 2709-2711.	1.5	5
117	Improved electrical stability in asymmetric fingered polysilicon thin film transistors. Applied Physics Letters, 2006, 89, 123506.	1.5	5
118	Flexible PVDF-TrFE Pyroelectric Sensor Integrated on a Fully Printed P-channel Organic Transistor. Procedia Engineering, 2012, 47, 526-529.	1.2	5
119	Reduction of Short Channel Effects and Hot Carrier Induced Instability in Fully Self-Aligned Gate Overlapped Lightly Doped Drain Polysilicon TFTs. Journal of Display Technology, 2012, 8, 18-22.	1.3	5
120	Fully-organic flexible tactile sensor for advanced robotic applications. , 2014, , .		5
121	Pd-Gate a-Si:H Thin-Film Transistors as Hydrogen Sensors. Japanese Journal of Applied Physics, 1990, 29, L2357-L2359.	0.8	4
122	Hot-carrier-induced modifications to the noise performance of polycrystalline silicon thin-film transistors. Applied Physics Letters, 1997, 71, 1216-1218.	1.5	4
123	Channel doping effects in poly-Si thin film transistors. Thin Solid Films, 2005, 487, 242-246.	0.8	4
124	Dopant and defect interactions in polycrystalline silicon thin-film transistors. Journal of Applied Physics, 2005, 97, 104515.	1.1	4
125	Very High Performance GaN HEMT devices by Optimized Buffer and Field Plate Technology. , 2006, ,		4
126	Hot Carrier Effects in p-Channel Polycrystalline Silicon Thin Film Transistors Fabricated on Flexible Substrates. Japanese Journal of Applied Physics, 2007, 46, 1299-1302.	0.8	4

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127	Insight into excimer laser crystallization exploiting ellipsometry: Effect of silicon film precursor. Thin Solid Films, 2007, 515, 7508-7512.	0.8	4
128	Growth and Manipulation of Organic Semiconductors Microcrystals by Wet Lithography. Advanced Functional Materials, 2016, 26, 2387-2393.	7.8	4
129	Hydrogen effects on a-SiO2: A photoemission study. Journal of Non-Crystalline Solids, 1991, 137-138, 1079-1082.	1.5	3
130	Hot carriers effects in polycrystalline silicon thin-film transistors. Microelectronic Engineering, 1992, 19, 109-112.	1.1	3
131	Excimer laser annealing of shallow As and B doped layers. Materials Science and Engineering B: Solid-State Materials for Advanced Technology, 2004, 114-115, 352-357.	1.7	3
132	Excimer laser annealing of B and BF2 implanted Si. Materials Science and Engineering B: Solid-State Materials for Advanced Technology, 2005, 124-125, 232-234.	1.7	3
133	Improved electrical stability in asymmetric fingered polysilicon thin film transistors. Thin Solid Films, 2005, 487, 237-241.	0.8	3
134	Annealing temperature effects on the electrical characteristics of p-channel polysilicon thin film transistors. Journal of Non-Crystalline Solids, 2006, 352, 1723-1727.	1.5	3
135	Electrical instability in self-aligned p-channel polysilicon TFTs related to damaged regions present at the gate edges. Solid-State Electronics, 2008, 52, 406-411.	0.8	3
136	(Invited) Downscaling Issues in Polycrystalline Silicon TFTs. ECS Transactions, 2010, 33, 3-22.	0.3	3
137	(Invited) Contact Effects in Organic Thin Film Transistors with Different Device Structures. ECS Transactions, 2014, 64, 131-142.	0.3	3
138	Graphene-based field effect transistors for radiation-induced field sensing. Nuclear Instruments and Methods in Physics Research, Section A: Accelerators, Spectrometers, Detectors and Associated Equipment, 2016, 824, 392-393.	0.7	3
139	Theoretical Analysis of a-Si:H Based Multilayer Structure Thin Film Transistors. Japanese Journal of Applied Physics, 1990, 29, 1634-1638.	0.8	2
140	Chemically sensitive hydrogenated amorphous silicon thin-film transistors. Journal of Non-Crystalline Solids, 1991, 137-138, 1253-1256.	1.5	2
141	Application of the photo induced discharge technique for the investigation of a-Si:H thin-film transistor instability. Journal of Non-Crystalline Solids, 1993, 164-166, 735-738.	1.5	2
142	<title>High-electric-field phenomena in polycrystalline silicon thin film transistors</title> . , 1997, , .		2
143	Excess noise in polysilicon thin film transistors operated in kink regime. Electronics Letters, 1997, 33, 2075.	0.5	2
144	Boron-enhanced diffusion in excimer laser annealed Si. Materials Science and Engineering B: Solid-State Materials for Advanced Technology, 2004, 114-115, 114-117.	1.7	2

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145	Silicon dioxide deposited by ECR-PECVD for low-temperature Si devices processing. Microelectronics Reliability, 2005, 45, 879-882.	0.9	2
146	Boron distribution in silicon after excimer laser annealing with multiple pulses. Materials Science and Engineering B: Solid-State Materials for Advanced Technology, 2005, 124-125, 228-231.	1.7	2
147	Ultra-shallow junction by laser annealing: Integration issues and modelling. Nuclear Instruments & Methods in Physics Research B, 2006, 253, 1-8.	0.6	2
148	Excimer Laser Annealing for Low-Temperature Polysilicon Thin Film Transistor Fabrication on Plastic Substrates. , 2007, , .		2
149	Asymmetric fingered polysilicon p-channel thin film transistor structure for kink effect suppression. Thin Solid Films, 2007, 515, 7433-7436.	0.8	2
150	Edge Effects in Self-Heating-Related Instabilities in p-Channel Polycrystalline-Silicon Thin-Film Transistors. IEEE Electron Device Letters, 2011, 32, 1707-1709.	2.2	2
151	(Invited) Short Channel Effects and Drain Field Relief Architectures in Polysilicon TFTs. ECS Transactions, 2011, 37, 3-14.	0.3	2
152	A large signal non quasi static compact model for printed organic thin film transistors. , 2016, , .		2
153	Staggered top-gate PDIF-CN2 N-type thin film transistors on flexible plastic substrates. Organic Electronics, 2018, 57, 226-231.	1.4	2
154	Effects of illumination on the electrical characteristics in organic thin-film transistors based on dinaphtho [2,3-b:2′,3′-f] thieno[3,2-b] thiophene (DNTT): Experiment and modeling. Synthetic Metals, 2022 283, 116985.	2, 2.1	2
155	Properties of amorphous Si: H films prepared by dual ion beam sputtering. Physica Scripta, 1988, 37, 828-830.	1.2	1
156	Short-channel effects in 0.2 μm channel length a-Si:H thin-film transistors fabricated by electron beam lithography. Journal of Non-Crystalline Solids, 1991, 137-138, 1225-1228.	1.5	1
157	Instability in hydrogenated amorphous silicon/amorphous silicon dioxide thin-film transistors: Evidence for a predominant effect of charge trapping into the gate insulator. Philosophical Magazine Letters, 1992, 65, 177-182.	0.5	1
158	Comparative analysis of advanced poly-silicon thin-film transistor architectures for drain field relief. , 2003, 5004, 150.		1
159	Effects of Fabrication Parameters on the Electrical Stability of Gate Overlapped Lightly Doped Drain Polysilicon Thin-Film Transistors. Japanese Journal of Applied Physics, 2006, 45, 4384-4388.	0.8	1
160	Bragg reflector based gate stack architecture for process integration of excimer laser annealing. Applied Physics Letters, 2006, 89, 253502.	1.5	1
161	RBS-channeling analysis of ion-irradiation effects in heavily-doped Si:As. Nuclear Instruments & Methods in Physics Research B, 2007, 257, 253-256.	0.6	1
162	Chemoresistive nanofibrous sensor array and read-out electronics on flexible substrate. , 2009, , .		1

162 Chemoresistive nanofibrous sensor array and read-out electronics on flexible substrate. , 2009, , .

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163	(Invited) Contact Effects in Organic and Inorganic Thin Film Transistors. ECS Transactions, 2013, 54, 171-185.	0.3	1
164	Water stable organic thin film transistors (TFTs) made on flexible substrates. , 2015, , .		1
165	Contact Effects in Organic Thin-Film Transistors: Device Physics and Modeling. , 2016, , 945-969.		1
166	Logic gates and memory elements design and simulation using PMOS organic transistor. , 2017, , .		1
167	Electrical instability in short channel organic thin-film transistors induced by lucky-polaron mechanism. Organic Electronics, 2021, 98, 106279.	1.4	1
168	Theory for field-effect mobility enhancement in multilayer structure thin-film transistors. Journal of Non-Crystalline Solids, 1989, 115, 102-104.	1.5	0
169	A Critical Assessment of Different Models of the Metastability in a-Si:H. Japanese Journal of Applied Physics, 1998, 37, 1736-1746.	0.8	Ο
170	Low-frequency excess noise induced by hot-carrier injection in polysilicon thin-film transistors. Thin Solid Films, 2001, 383, 147-150.	0.8	0
171	Mechanisms of Dopant Redistribution and Retention in Silicon Following Ultra-low Energy Boron Implantation and Excimer Laser Annealing. , 2002, , .		0
172	Computational methods for the simulation of the excimer laser annealing in MOS technology. Materials Science and Engineering B: Solid-State Materials for Advanced Technology, 2004, 114-115, 100-104.	1.7	0
173	Grain Boundary Characterisation in Sequentially Laterally Solidified Polycrystalline-Silicon Thin Film Transistors. ECS Transactions, 2007, 8, 211-216.	0.3	ο
174	Hydrogen-induced Nitrogen Passivation in Dilute Nitrides: A Novel Approach to Defect Engineering. Materials Research Society Symposia Proceedings, 2007, 994, 1.	0.1	0
175	In-Plane Band Gap Engineering by Hydrogenation of Dilute Nitride Semiconductors. AIP Conference Proceedings, 2007, , .	0.3	Ο
176	Excimer Laser Annealing of Ion-Implanted Silicon: Dopant Activation, Diffusion and Defect Formation. , 2007, , .		0
177	(Invited) Printed Organic TFTs on Flexible Substrate for Complementary Circuits. ECS Transactions, 2013, 54, 153-163.	0.3	Ο
178	Investigation of Gate Direct-Current and Fluctuations in Organic p-Type Thin-Film Transistors. IEEE Electron Device Letters, 2016, 37, 1625-1627.	2.2	0
179	Historical evolution of pulsed laser annealing for semiconductor processing. , 2021, , 1-48.		0
180	TECHNOLOGY OF LARGE AREA TWO-DIMENSIONAL COLOR IMAGE SENSOR. , 2000, , .		0

#	Article	IF	CITATIONS
181	Contact Effects in Organic Thin-Film Transistors: Device Physics and Modeling. , 2016, , 1-25.		0